

[illegible]

Application Number
09/887.875

Natsuki KUSHIYAMA

Group Art Unit
2181

[illegible]

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
<i>April</i>	58-182321	10/25/83	JAPAN	<i>1</i>	<i>1</i>		X
<i>April</i>	2000-0004505	01/25/00	KOREA	<i>1</i>	<i>2</i>		X

EXAMINER
April Sharon

21/23/04

\\LA-81790-0204-167569 v1

Application Number
09/887,875

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U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
Copy	11-97628	04/09/99	JAPAN	_____	_____	Abstract	
Copy	11-204740	07/30/99	JAPAN	_____	_____	Abstract	
Copy	11-312785	11/09/99	JAPAN	_____	_____	Abstract	
Copy	2000-68458	03/03/00	JAPAN	_____	_____	Abstract	
Copy	05-29464	02/05/93	JAPAN	_____	_____	Abstract	

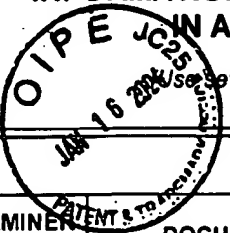
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Apel Sharon

21/23/04

\\LA-81790-0204-184256 v1

FORM PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION <small>Use several sheets if necessary)</small>	Docket Number (Optional) 81790.0204	Application Number 09/887,875
	Applicant Natsuki KUSHIYAMA	
	Filing Date June 22, 2001	Group Art Unit 2181



U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

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 JAN 22 2004
 Technology Center 2100

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>Ayel</i>	SUZUKI, et al., "Analytical Surface Potential Expression for Double Gate SOI MOSFET," International Workshop on VLSI Process and Device Modeling, pp. 150-151 (May 14-15, 1999)
<i>Ayel</i>	YOO, et al., "Double Gate Poly Si TFT," Fourth Asian Symposium on Information Display, pp. 219-222 (Feb. 13-14, 1997)
<i>Ayel</i>	WONG, et al., "Double Gate SOI MOSFET," International Electron Device Meeting, 15, 2.1-4 (December 1998)

EXAMINER <i>Ayel Shaper</i>	DATE CONSIDERED <i>11/23/04</i>
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.	